

DOCKET NO: 250327US-2S



IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF :
SHINICHI YOSHIOKA : EXAMINER: FLORES, LEON
SERIAL NO: 10/798,403 :
FILED: MARCH 12, 2004 : GROUP ART UNIT: 2611
FOR: SEMICONDUCTOR INTEGRATED :
CIRCUIT DEVICE AND METHOD OF
TESTING THE SAME

AMENDMENT

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Office Action of April 24, 2007, please amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 4 of this paper.

Remarks begin on page 13 of this paper.